

REVISIONS 1776001 APPROVAL DESCRIPTION DATE REPLACES REVE WITH CHANGES PER TDRR 00562 LICENSING THE HOLDER OR ANY OTHER PERSON OR CORPORATION, OR CONVEY-ING ANY RIGHTS OR PERMISSION TO MANUFACTURE, USE, OR SELL ANY PATENTED INVENTION THAT MAY IN ANY WAY BE RELATED THERETO. NOTES (CONTINUED): TEST METHODS: (REF. MIL-STD-750 WITH EXCEPTIONS NOTED BELOW). (1) LEAD FATIGUE: LEADS SHALL BE CAPABLE OF WITHSTANDING THE FOLLOWING LEAD BEND TEST. THE UNIT SHALL BE HELD IN A VERTICAL POSITION WITH A ONE POUND WEIGHT SUSPENDED FROM THE LEAD TO BE TESTED. TWO CYCLES OF BENDING SHALL BE PERFORMED, A CYCLE CONSISTING OF MOVING THE BODY OF THE UNIT, 90 DEGREES FROM THE VERTICAL IN ONE DIRECTION, AND BACK 90 DEGREES TO THE ORIGINAL POSITION. NO MECHANICAL DAMAGE SHALL BE EVIDENCED AFTER THE TEST. (2) LEAD TENSION: EACH LEAD SHALL BE CAPABLE OF WITHSTANDING AN AXIAL PULL OF 4 POUNDS MINIMUM FOR 30 SECONDS. NO MECHANICAL DAMAGE SHALL BE EVIDENCED AFTER THE TEST. (3) SEAL TEST: THE UNITS SHALL BE SUBJECTED TO A HELIUM OR RADIFLO LEAK DETECTION TEST WITH A SENSITIVITY OF AT LEAST 1 X 10-7 CC/ATM/SEC. A LEAKAGE RATE OF 1 X 10-6 CC/ATM/SEC OR GREATER SHALL CONSTITUE A FAILURE. (4) AVERAGE PROPAGATION DELAY (Tp): MEASUREMENTS SHALL BE PERFORMED ON ANY ONE INPUT USING TEST CIRCUIT SPECIFIED IN FIGURE 1 MADE UP OF ACCEPTABLE UNITS WHERE $T_P = (T_1 + T_2)/2$. VOLTAGE PIN 8 TO PIN 4,3 V ± 10%. (5) POWER BURN-IN: AN ODD NUMBER OF UNITS (GATES) SHALL BE CONNECTED IN SERIES WITH THE OUTPUT OF THE LAST UNIT SUPPLYING THE INPUT TO THE FIRST UNIT, THUS FORMING A "RING" AS SHOWN IN FIGURE 2. WHEN 8 V ± 5% DC IS APPLIED TO THE POWER TERMINALS OF ALL UNITS IN THE CIRCUIT ("RING"), OSCILLATION SHALL OCCUR AT THE INITIATION OF THE TEST. (6) VISUAL AND MECHANICAL EXAMINATION: MARKING SHALL BE LEGIBLE, THE CASE FINISH SHALL HAVE NO PITS, FLAKING OR CHIPPING, LEADS SHALL BE FREE FROM TABLE I KINKS AND NICKS AND COMPLY WITH THE SPECIFIED LEAD MATERIAL REQUIREMENT. PRE-ELECTRICAL TEST PROCESSING GLASS IN HEADER SHALL HAVE NO CRACKS, CHIPS OR BUBBLES. TEST CONDITIONS TEST 1 TO 500 **OVER 500** (7) THE UNITS WILL BE OPENED AND EXAMINED UNDER 80% MAGNIFICATION FOR DEFECTS IN THE METALIZED INTERCONNECTION PATTERNS WHICH ARE OR COULD BE DUE TO 100% METHOD 1056, CONDITION B THERMAL SHOCK MECHANICAL ABRASION OR CHEMICAL REACTION WITH CONTAMINATE SUBSTANCES. REQUIREMENT (+150°C TO -65°C, 3 CYCLES) DEFECTS IN THE METALIZATION WILL BE CAUSE FOR REJECTION. TEMPERATURE = 150° ± 5°C. HIGH TEMPERATURE BAKE E. THE SUPPLIER SHALL CONFORM TO THE QUALITY ASSURANCE PROVISIONS SPECIFIED IN 72 +8 HOURS. ND 1015404, CLASS 1. 4. INTERPRET DRAWING IN ACCORDANCE WITH STANDARDS PRESCRIBED BY MIL-D-70327. METHOD 2006 (20,000 G) Y1 DIRECTION CONSTANT ACCELERATION METHOD 1026 POWER, BURN-IN SEE NOTE 3 D (5) AND FIGURE 2 TA = +22°C MIN; IN FREE AMBIENT AIR t = 168 +12 HOURS REQUIREMENT 100% SEE NOTE 3 D (3) SEAL TEST (H) REPLACES REVE WITH CHANGES FIND NOMENCLATURE OR PART OR DESCRIPTION IDENTIFYING NO. LIST OF MATERIALS MIT UNLESS OTHERWISE SPECIFIED MANNED SPACECRAFT CENTER INSTRUMENTATION LAB DIMENSIONS ARE IN INCHES HOUSTON, TEXAS **TOLERANCES ON** DRAWN Reas DATE 129463 DECIMALS MICRO-NOR GATE (TO 47 SIZE) DO NOT SCALE THIS DRAWING SPECIFICATION CONTROL DRAWING MATERIAL NASA DRAWING NO. HEAT TREATMENT NASA APPROVAL W. A. A. 1006771 USED ON **NEXT ASSY** FINAL FINISH SHEET 2 OF 4 APPLICATION

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